

DESIGN/PROCESS CHANGE NOTIFICATION

This is to inform you that a change is being made to the products listed below.

Unless otherwise indicated in the details of this notification, the identified change will have no impact on product quality, reliability, electrical, visual or mechanical performance and affected products will remain fully compliant to all published specifications. Products incorporating this change may be shipped interchangeably with existing unchanged products.

This change is planned to take effect in 90 calendar days from the date of this notification. Please work with your local Fairchild Sales Representative to manage your inventory of unchanged product if your evaluation of this change will require more than 90 calendar days.

Please contact your local Customer Quality Engineer within 30 days of receipt of this notification if you require any additional data or samples. Alternatively, you may send an email request for data, samples or other information to PCNSupport@fairchildsemi.com.

Implementation of change:

Expected First Shipment Date for Changed Product : Apr. 09, 2012

Expected First Date Code of Changed Product :1205

Last Date for Shipment of Unchanged Product : Apr. 09, 2012

Description of Change (From) :

431 shunt regulator products identified in the Affected FSID list don't have PSPI(Photo Sensitive Poly Imide) layer on the die passivation.

Description of Change (To) :

PSPI layer will be added on the current existing die passivation for 431 shunt regulator products identified in the Affected FSID list.

Reason for Change:

PSPI layer will enhance the protection of die surface.

There will be no change for the current existing process including passivation except adding PSPI layer.

Affected products will remain fully compliant to all published specifications.

This change is planned to take effect in 90 calendar days from the date of this notification.

Please work with your local Fairchild Sales representative to manage your inventory of unchanged product if your evaluation of this change will require more than 90 calendar days.

Please contact your local Customer Quality Engineer within 30 days of receipt of this notification if you require any additional data or samples.

Affected Product(s):

FAN431AZXA	FAN431LZXA	KA431AZBU
KA431AZTA	KA431LZTA	LM431ACZ
LM431ACZX	LM431AIZ	LM431BCZX
LM431BCZXA	LM431BCZXA_G	LM431BIZX
LM431CCZ	LM431CCZXA	LM431SBCMLX
LM431SCCMLX		

Qualification Plan	Device	Package	Process	No. of Lots
Q20110444	KA431LZ	TO92R003	BHB4	2

Test Description:	Condition:	Standard :	Duration:	Results:
High Temperature Operation Life	125C		1000 hrs	0/154
High Temperature Storage Life	150C	JESD22-A103	1000 hrs	0/154
Temperature Cycle	-65C, 150C	JESD22-A104	500 cycles	0/154
Temperature Humidity Biased Test	85C, 85%RH, 37V	JESD22-A101	1000 hrs	0/154

Qualification Plan	Device	Package	Process	No. of Lots
Q20110444	LM431BCZ	TO92R003	BHB4	1

Test Description:	Condition:	Standard :	Duration:	Results:
High Temperature Operation Life	125C		1000 hrs	0/77
High Temperature Storage Life	150C	JESD22-A103	1000 hrs	0/77
Temperature Cycle	-65C, 150C	JESD22-A104	500 cycles	0/77
Temperature Humidity Biased Test	85C, 85%RH, 37V	JESD22-A101	1000 hrs	0/77